

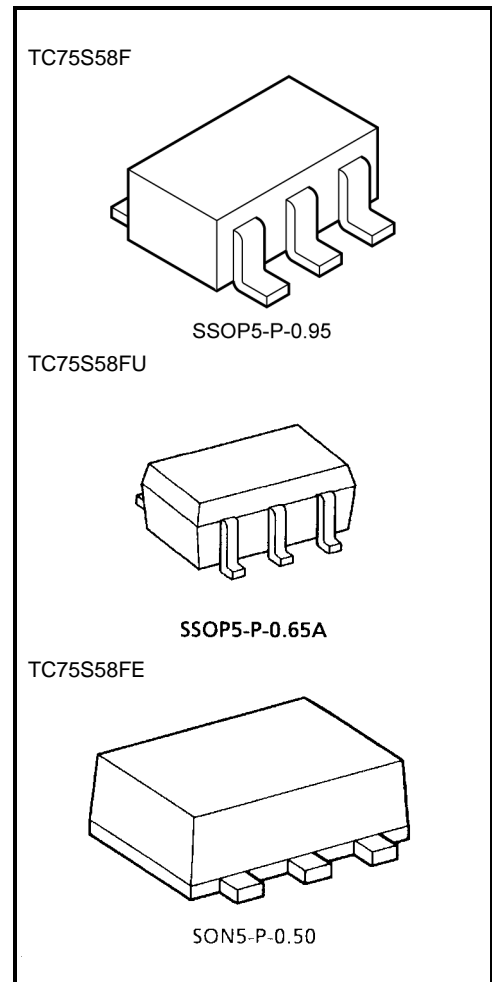
TC75S58F, TC75S58FU, TC75S58FE

Single Comparator

The TC75S58F/TC75S58FU/TC75S58FE is a CMOS general-purpose single comparator. The device can operate off a single power supply and draws a lower supply current than a conventional bipolar general-purpose comparator. This device's open-drain output stage can be wire-ORed with those of other open-drain output circuits.

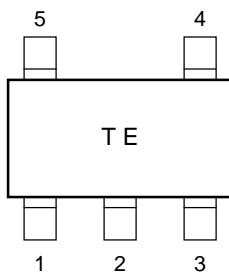
Features

- Low-current power supply : $I_{DD} = 10 \mu A$ (typ.)
- Single power supply operation
- Wide common mode input voltage range: $V_{SS} \sim V_{DD} - 0.9 V$
- Open drain output circuit
- Low input bias current
- Small package

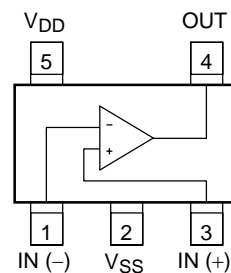


Weight
 SSOP5-P-0.95 : 0.014 g (typ.)
 SSOP5-P-0.65A : 0.006 g (typ.)
 SON5-P-0.50 : 0.003 g (typ.)

Marking (top view)



Pin Connection (top view)



Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Supply voltage		V_{DD}, V_{SS}	± 3.5 or 7	V
Differential input voltage		DV_{IN}	± 7	V
Input voltage		V_{IN}	$V_{SS} \sim V_{DD}$	V
Output current		I_O	± 35	mA
Power dissipation	TC75S58F/FU	P_D	200	mW
	TC75S58FE		100	
Operating temperature		T_{opr}	-40~85	°C
Storage temperature		T_{stg}	-55~125	°C

Note: This device's CMOS structure makes it prone to latch-up. To prevent latch-up, please take the following precautions:

- Ensure that no I/O pin's voltage level ever exceeds V_{DD} or drops below V_{SS} . In addition, check the power-on timing.
- Do not subject the device to excessive noise.

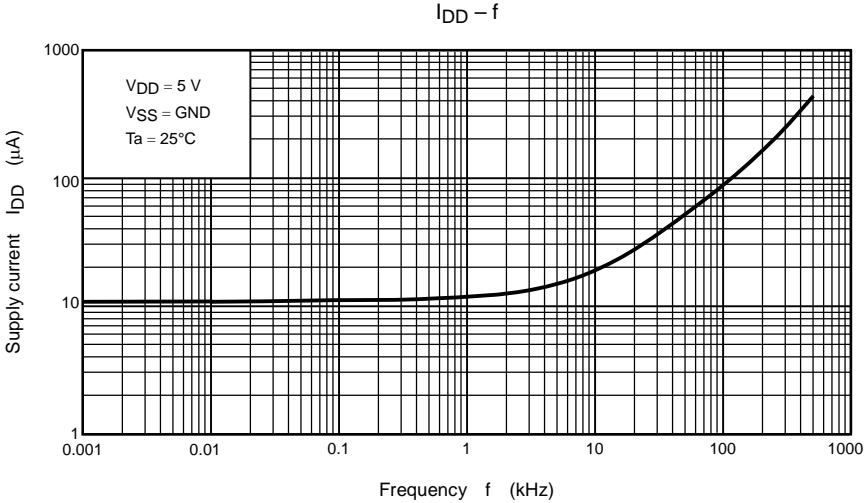
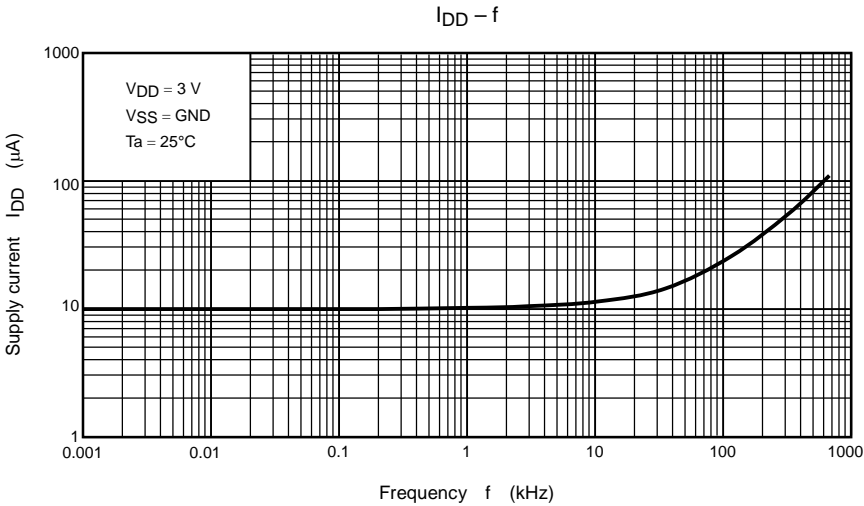
Electrical Characteristics ($V_{DD} = 5\text{ V}$, $V_{SS} = \text{GND}$, $T_a = 25^\circ\text{C}$)

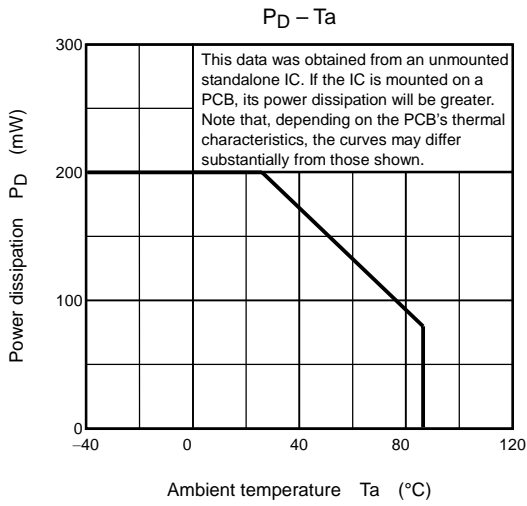
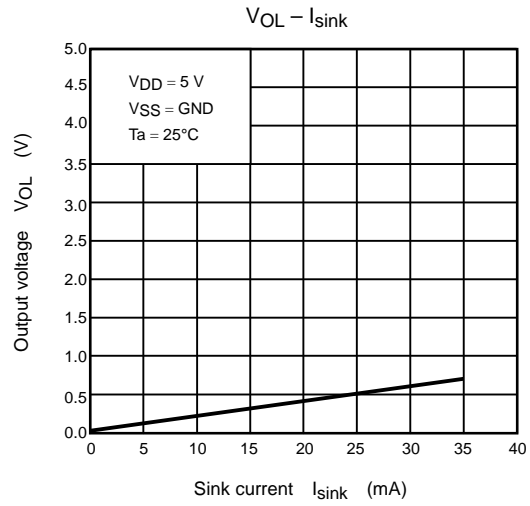
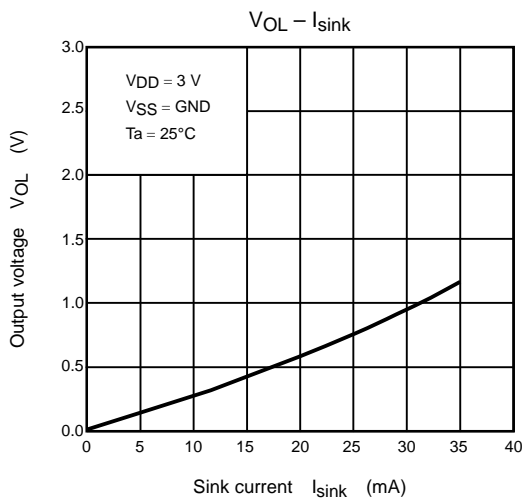
Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Input offset voltage	V_{IO}	—	—	—	± 1	± 7	mV
Input offset current	I_{IO}	—	—	—	1	—	pA
Input bias current	I_I	—	—	—	1	—	pA
Common mode input voltage	CMV_{IN}	—	—	0	—	4.1	V
Supply current	I_{DD} (Note)	—	—	—	11	22	μA
Voltage gain	G_V	—	—	—	94	—	dB
Sink current	I_{sink}	—	$V_{OL} = 0.5\text{ V}$	13	25	—	mA
Output leak current	I_{LEAK}	—	$V_O = 5\text{ V}$	—	5	—	nA
Output voltage	V_{OL}	—	$I_{sink} = 5.0\text{ mA}$	—	0.1	0.3	V
Operating supply voltage	V_{DD}	—	—	1.8	—	7.0	V
Propagation delay time (turn on)	t_{PLH} (1)	—	Over drive = 100 mV	—	800	—	ns
	t_{PLH} (2)	—	TTL step input	—	620	—	
Propagation delay time (turn off)	t_{PHL} (1)	—	Over drive = 100 mV	—	230	—	ns
	t_{PHL} (2)	—	TTL step input	—	350	—	
Response time	t_{TLH}	—	Over drive = 100 mV	—	190	—	ns
	t_{THL}	—	Over drive = 100 mV	—	6	—	

Electrical Characteristics ($V_{DD} = 3\text{ V}$, $V_{SS} = \text{GND}$, $T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Input offset voltage	V_{IO}	—	—	—	± 1	± 7	mV
Input offset current	I_{IO}	—	—	—	1	—	pA
Input bias current	I_I	—	—	—	1	—	pA
Common mode input voltage	CMV_{IN}	—	—	0	—	2.1	V
Supply current	I_{DD} (Note)	—	—	—	10	20	μA
Sink current	I_{sink}	—	$V_{OL} = 0.5\text{ V}$	6	18	—	mA
Output leak current	I_{LEAK}	—	$V_O = 3\text{ V}$	—	5	—	nA
Output voltage	V_{OL}	—	$I_{sink} = 5.0\text{ mA}$	—	0.15	0.35	V
Propagation delay time (turn on)	t_{PLH}	—	Over drive = 100 mV	—	590	—	ns
Propagation delay time (turn off)	t_{PHL}	—	Over drive = 100 mV	—	230	—	ns
Response time	t_{TLH}	—	Over drive = 100 mV	—	170	—	ns
	t_{THL}	—	Over drive = 100 mV	—	5	—	

Note: This device's current consumption increases as its operating frequency increases. Note that the power dissipation should not exceed the allowable power dissipation.

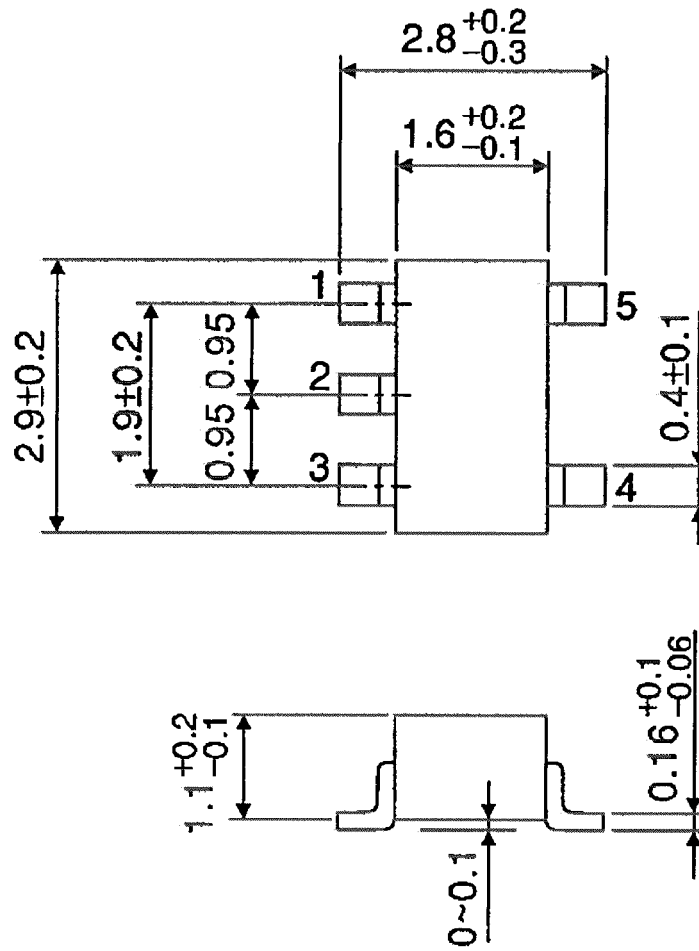




Package Dimensions

SSOP5-P-0.95

Unit : mm

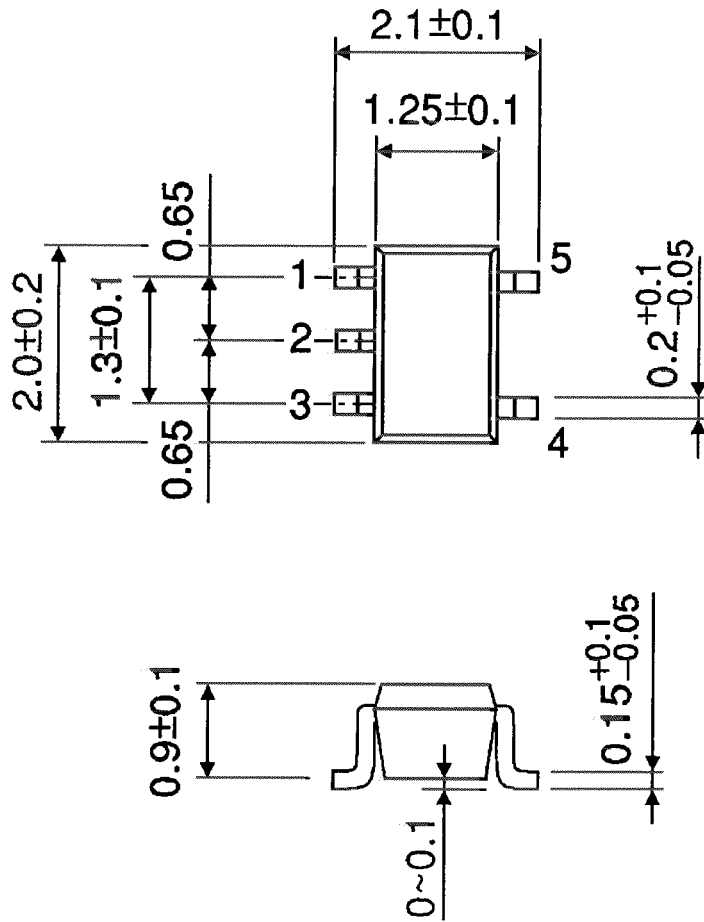


Weight: 0.014 g (typ.)

Package Dimensions

SSOP5-P-0.65A

Unit : mm

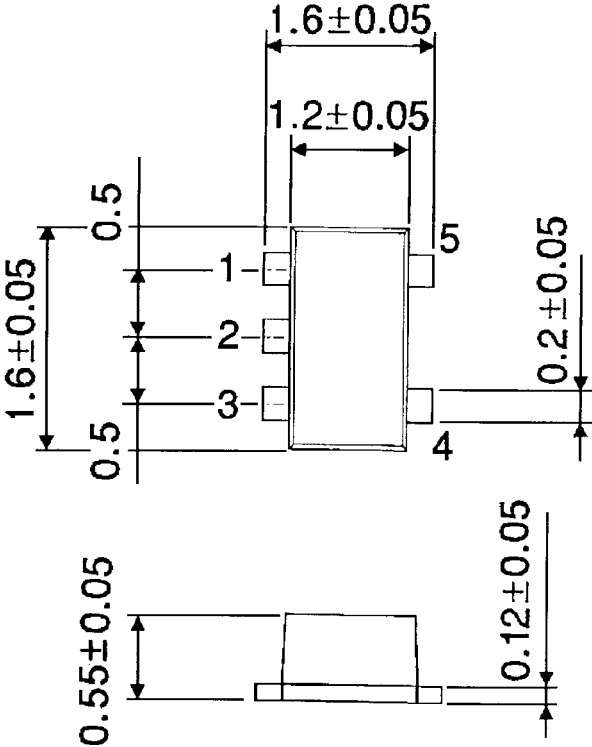


Weight: 0.006 g (typ.)

Package Dimensions

SON5-P-0.50

Unit : mm



Weight: 0.003 g (typ.)

RESTRICTIONS ON PRODUCT USE

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